

L Number	Hits	Search Text	DB	Time stamp
1	494	33/645.cccls.	USPAT	2003/07/02 07:09
2	2131	430/22,311.cccls.	USPAT	2003/07/02 07:09
3	489	356/399.cccls.	USPAT	2003/07/02 07:09
4	0	250/491.2.cccls.	USPAT	2003/07/02 07:09
5	1136	438/706,717,725.cccls.	USPAT	2003/07/02 07:10
6	4195	33/645.cccls. 430/22,311.cccls. 356/399.cccls. 250/491.2.cccls.	USPAT	2003/07/02 07:10
7	405	438/706,717,725.cccls. (33/645.cccls. 430/22,311.cccls. 356/399.cccls. 250/491.2.cccls. 438/706,717,725.cccls.) and alignment near mark\$1	USPAT	2003/07/02 07:11
-	6399	alignment near mark\$1 and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/07/02 07:09
-	1787	(alignment near mark\$1 and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:02
-	559	expose\$3 near7 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
-	1427	expos\$3 near7 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
-	1210	expos\$3 near5 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
-	471	(expos\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 09:07
-	146	clear\$3 near5 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:08
-	69	(clear\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:08
-	77	(clear\$3 near5 (alignment near mark\$1) and semiconductor) not ((clear\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:11
-	0	chung near chieh and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:11
-	0	chuang near chieh and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	1	chuang near chieh and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	249	lin and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	121	(lin and alignment near mark\$1) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	3	("6057206" "6197481" "6207966").PN.	USPAT	2003/06/17 08:44

	16	("4981529" "5382545" "5407763" "5596230" "5686761" "5705080" "5733711" "5858588" "5882980" "5904563" "5923996" "5926720" "5943587" "6060787" "6100158" "6143622").PN.	USPAT	2003/06/17 08:47
	13	("3783044" "5128283" "5316966" "5356513" "5578519" "5627110" "5877562" "5889335" "5893744" "5911108" "5946583" "5950093" "5982044").PN.	USPAT	2003/06/17 08:58
	435	((expos\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist) not (clear\$3 near5 (alignment near mark\$1) and semiconductor)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 09:08
	13	((("6197481") or ("6184104") or ("6529274") or ("6049137") or ("4632724") or ("6057206") or ("5897371") or ("5899738") or ("5946583") or ("5627110") or ("5316966") or ("5902707") or ("5705320"))).PN.	USPAT	2003/06/23 13:26